Inelastic X-ray Scattering Spectroscopy

for Material Excitations

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Outline

- IXS & Low Energy Excitations in Materials
- Why Synchrotron Radiation?
- Resonant IXS
- Typical Beamlines for RIXS
- IXS for Dynamics
- Typical Beamline of IXS
- Summary

IXS

Inelastic X-ray Scattering Spectroscopy

Photon in-Photon out spectroscopy Hard & Soft x-ray energy range Energy, Momentum & polarizations of outcoming photons gives information about excitations



Resonant IXS (RIXS)

The incoming photon resonates by absorption edges

Non resonant IXS (IXS)

Scatters from Charge density distribution

Excitations

Low Energy Excitations: meV-eV Electronic: d-d, charge transfer Dynamic: phonons Magnetic: magnons

Measuring the energy-momentum dispersion of these excitations gives very important microscopic information of the sample under studies



Fields of Study

Condensed Matter Physics, Material Science Understand the physical properties like Transport properties, Quantum state, Phase transitions, Superconductivity mechanism, Charge Ordering Phenomenon, etc

Interests

Unconventional Superconductivity, High Tc superconductivity: cuprates & Fe based Manganite, Niclates Strongly Correlated Materials, Mott-Hubbard Insulators Semiconductors, etc

Samples



Ca Ba

YBCO High Tc Superconductor T_c~90 K Fe based Superconductor $T_c \sim 40 \text{ K}$

Synchrotron Radiation



SPring-8 Japan 1997 8 Gev, 1436 m

- Very High Brightness Source
- Very high photon flux
- Collimated beam
- Tuning the incoming energy
- Possible to reach very high energy resolution (ΔE/E~10⁻⁸)



Energy-momentum of Synchrotron Radiation



Resonant Inelastic X-ray Scattering

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Resonant inelastic x-ray scattering studies of elementary excitations

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In the past decade, resonant inelastic x-ray scattering (RIXS) has made remarkable progress as a spectroscopic technique. This is a direct result of the availability of high-brilliance synchrotron x-ray radiation sources and of advanced photon detection instrumentation. The technique's unique

Physical Process

Resonant Inelastic X-ray Scattering (RIXS)



Schematic picture is understood simply

But measuring data and interpreting the data has many challenges

Many works has been done to reach the state of the art of this measurement using synchrotron radiation

Progress



Energy Resolution improvements Count Rate increase Count rate/resolution increase

Increasing number of publications and citations



Decision for Absorption Edge



At First we may assume little difference between different Edge, but it is not!!

- Intensity changes with dioplar or quadropole transitions
- Using higher energy lets scans higher momentum transfer

1s to 4s transition is dipole, strong intensity and large momentum transfer Incident photon energy is tuned by energy scan measurement of absorption edge

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Reduction of Elastic Peak

Tail of the Elastic Scattering peak can hide or disturb the low energy inelastic peaks So it has to be reduced, determined and subtracted from the measured data

Main Contributions of the elastic peak

- Phonon

as much as 50 % of the peak Reduce the temperature as much as possible In long momentum transfer intensity α (q. δ)²

- Diffuse scattering due to the strain & defects



Energy & Resolutions

Energy transfer: Less than a few electron volts Energy Resolution: less than 100 meV For phonons ~meV

Soft X-ray: diffraction grating





Grating Equation: $m\lambda = d$ (sin $\alpha \pm \sin \beta$)

Hard X-ray: highly ordered crystalline lattice of Si, or Ge



RIXS Instrument

Experimental Instrument:

1- Beamline: deliver a well collimated, highly monochromatic, and often focused beam at sample

2- Spectrometer: sample environment, manipulate scattering angle, collect scatter radiation, energy analyzer

Two typical examples

Soft x-ray: ADRESS beamline and SAXES spectrometer Hard x-ray: MERIX-HERIXS bemline and MERIX spectrometer

ADRESS Beamline

ADvanced RESonant Spectroscopies (ADRESS) Beamline Swiss Light Source (SLS) For RIXS and ARPES studies on correlated & nano-strucured materials



SAXES Spectrometer

SuperAdvanced X-ray Emission Spectrometer (SAXES)



Spherical Variable Line Space (VLS) grating rather than a plane grating and concave collection mirror (minimize higher order optical aberrations in cost of reduced collection angle) 3200 mm⁻¹, R=58.55 m,

CCD detector Pixel size: 13.5*13.5 μm^2 Total resolving power ~ 10,000 in the whole energy range



Calculated performance of SAXES

MERIX Beamline

Example: BL30 ID APS, USA MERIX (Medium Energy Res. Inelas. X-ray) HERIX (High Energy Res Inelas. X-ray)



Source: two linear polarized Und, 2*2.5 m long, 30 mm period Energy Range~ 4.9-15 keV Energy Resolution ~ 70 meV; ΔE/E=1*10⁻⁵ Flux at sample (ph/s)=2*10¹² at 9 keV; Spot size=45*6 μm²-2.2*0.4 mm²₁₈

MERIXS Beamline

Monochromator: water cooled diamond(111) crystal

Secondary Monochromator: four asymmetrical cut Si(111) crystal, zero offset Constant band pass in the whole energy range~ 70 meV

Quickly Switch between high resolution narrow band with low flux to & low resolution and high flux

KB mirror to provide horizontal and vertical focusing

MERIX Spectrometer for analyze and detect the photons Used in 30 ID, APS 9ID, APS (2007) ID16, ESRF (2009) 11XU, SPring-8 (2001)



MERIXS & Total Energy Resolution

2 m detector arm Moves horizontally and vertically Rowland circle geometry

Analyzer is situated in He gas tank To minimize the absorption and background scattering



10 cm spherically bend, diced Ge(733) Bragg reflection at Cu K edge

Energy Resolution contribution:

- Intrinsic Darwin width
- Johan error in horizontal and vertical direction (increases quadratically with r/R)
- Finite beam footprint on the sample
- Finite block size (reduced linearly with size by using diced analyzer)

Total resolution at Cu K edge (FWHM)~ 83 meV For other transition metal K-edge ≤ 100 meV

Improving resolution by Saphire (AI_2O_3), Quartz (SiO₂), and LiNbO₃ is under progress

Typical Results

Comparison of $S(\omega)$ with the measured Im[-1/ $\epsilon(\omega)$] for various cuprates,

In comparison with EELS



Typical Results



Ti L3-edge RIXS spectra of Titanates



Cu K-edge RIXS spectra of La2CuO4 High Tc Cuprate superconductor

Inelastic X-ray Scattering

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Phonon spectroscopy by inelastic x-ray scattering

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The present synchrotron sources with brilliant x-ray beams, due to high photon fluxes, small source sizes and high collimation, have revolutionized x-ray physics.

Enormous progress has been initiated in all established x-ray methods, with the aim of the development of new types of spectroscopy. This is particularly true for the spectroscopy of the dynamics in condensed matter. Meanwhile, there are two powerful x-ray methods with very high-energy resolution available for the study of low energetic excitations like phonons.

This review summarizes the developments of these methods focusing on these instrumental developments of the spectrometers using either crystal optics in close-to-backscattering geometry or nuclear resonant techniques.

Applications to measurements of phonon dispersion curves and of phonon density of states

IXS for Phonon

Measuring dynamical properties give very important physical and chemical properties of materials like specific heat capacity, heat transport, electron transport, sounds, etc

In molecules

specific vibration modes for each bond can be measured by Raman

In Solids

The phonon mode has dispersion with momentum The dispersions can be measured by NIS or XIS





Beamline Layout

ESRF







High Energy Resolution



Experimental Condition

Location	INELAX	ID16	3ID	BL35XU		
	HASYLAB	ESRF	APS	SPring-8		
	Hamburg, Germany	Grenoble, France	Chicago, USA	Kansai, Japan		
Operational	1987	1994	1997	2000		
Source characteristics						
Ring energy	4.5 GeV	6.0 GeV	7.0 GeV	8.0 GeV		
Ring current	140 mA	200 mA	100 mA	100 mA		
Insertion device	wiggler	2 undulators	undulator	undulator		
Length	2.6 m	1.6 m each	2.5 m	4.5 m		
Divergence:						
vertical	0.12 mrad	24 μ rad	12 μ rad	11 μ rad		
horizontal	2.6 mrad	40 μ rad	42 μ rad	35 μ rad		
X-ray optics						
Pre-	Si (1 1 1)	Si (1 1 1)	diamond	Si (1 1 1)		
monochromator	2-crystal setting	channel-cut	2-crystal setting	2-crystal setting		
	room temperature	at 90–120 K	room temperature	cryogenically cooled		
Main	Si(h h h)	Si(h h h)	Si (4 4 0) + (15 11 3)	Si(h h h)		
monochromator	backscattering	backscattering	nested channel-cut	backscattering		
	spherically bent	flat		flat		
		focusing mirror	focusing mirror	focusing mirror		
Focus spot	$3 \times 1 \ \mathrm{mm}^2$	$500 \times 300 \ \mu m^2$	$600 \times 500 \ \mu m^2$	$100 \times 150 \ \mu m^2$		
Analyser	Si(h h h)	Si(h h h)	Si(h h h)	Si(h h h)		
-	spherically bent	spherically bent	spherically bent	spherically bent		

Table 2. Comparison of backscattering spectrometers at HASYLAB, at the ESRF, at APS and SPring-8.

Examples

Softening of Cu-O Bond Stretching Phonons in Tetragonal $HgBa_2CuO_{4+\delta}$

H. Uchiyama,¹ A. Q. R. Baron,² S. Tsutsui,² Y. Tanaka,³ W.-Z. Hu,¹ A. Yamamoto,¹ S. Tajima,¹ and Y. Endoh⁴



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BL35- Inelastic X-ray Scattering

 BL22XU JAEA Quantum Structural Science (Japan Atomic Energy Agency) Medical and Imaging | BL20B2 ¥ BL23SU JAEA Actinide Science (Japan Atomic Energy Agency) Medical and Imaging II BL20XU ¥ BL24XU Hyogo ID (Hyogo Prefecture) Engineering Science Research | BL19B2 ¥ ¥ BL25SU Soft X-ray Spectroscopy of Solid RIKEN SR Physics BL19LXU . BL26B1 RIKEN Structural Genomics I RIKEN Coherent Soft X-ray Spectroscopy BL17SU BL26B2 RIKEN Structural Genomics II Sunbeam BM BL16B2 ¥ BL27SU Soft X-ray Photochemistry (Industrial Consortium) Sunbeam ID BL16XU . O BL28XU Advanced Basic Science for Battery Innovation (ABSBI) (Industrial Consortium) (Kyoto University) WEBRAM BL15XU . 29 28 27 26 25 24 # BL28B2 White Beam X-ray Diffraction (National Institute for Materials Science) 23 22 21 BL29XU RIKEN Coherent X-ray Optics 30 Engineering Science Research II BL14B2 ¥ BL32XU RIKEN Targeted Proteins 20 JAEA Materials Science BL14B1 ● SPring 22 BL32B2 Pharmaceutical Industry (Japan Atomic Energy Agency) 33 (Pharmaceutical Consortium for Protein Structure Analysis) Surface and Interface Structures BL13XU ¥ 34 BL33XU TOYOTA NSRRC BM BL12B2 (TOYOTA Central R&D Labs., Inc.) 35 (National Synchrotron Radiation Research Center) BL33LEP Laser-Electron Photon Beamline Map 36 NSRRC ID BL12XU . 15 search Center for Nuclear Physics, Osaka I (National Synchrotron Radiation Research Center) 37 BL35XU High Resolution Inelastic Scattering 14 JAEA Quantum Dynamics BL11XU Total number of beamlines : 62 38 13 BL37XU Trace Element Analysis (Japan Átomic Energy Agency) Insertion Device (6 m) ¥ BL38B1 Structural Biology III 39 12 High Pressure Research BL10XU ¥ Insertion Device (30 m) 40 BL38B2 Accelerator Beam Diagnosis Nuclear Resonant Scattering BL09XU ¥ Bending Magnet : 24 (----= BL39XU Magnetic Materials 41 Hyogo BM (Hyogo Prefecture) BL08B2 ● ¥ BL40XU High Flux High Energy Inelastic Scattering BL08W ¥ ¥ BL40B2 Structural Biology II Univ-of-Tokyo BL07LSU ● (The University of Tokyo) ¥ BL41XU Structural Biology I 47 48 Accelerator Beam Diagnosis BL05SS BL431R Infrared Materials Science High Energy X-ray Diffraction BL04B2 ¥ BL43LXU RIKEN Quantum Nano Dynamics High Temperature and High Pressure Research BL04B1 ¥ BL44XU Macromolecular Assemblies (Institute for Protein Research, Osaka University) Advanced Softmaterial BL03XU (Advanced Softmaterial Beamline Consortium) BL44B2 RIKEN Materials Science Main Bldg. Powder Diffraction BL02B2 ¥ BL45XU RIKEN Structural Biology I Single Crystal Structure Analysis BL02B1 ¥ BL46XU Engineering Science Research III. ¥ BL47XU HXPES+MCT XAFS BL01B1 ¥



Energy (kcV)	Si Order	Resolution (mcV)	Flux at Sample (GHz)
15.816	(888)	6	30
17.794	(999)	3	10
21,747	(11 11 11)	1.5	3.5
25,702	(13 13 13)	1.0	0.8

Experimental Station

Phonon Spectrum

Momentum & Doping dependence

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Summarize

Many attempts has been done in the recent years to develop RIXS and IXS experimental techniques for measuring the low energy excitations

Using synchrotron radiation and technological improvement in the beamline and spectrometers now it is possible to reach very high resolution measurement of this excitations in wide range of momentum

Different beamline in modern synchrotrons are active for these measurements

For variety of complicated physical systems like manganites, high-Tc superconductors, strongly correlated systems, etc the techniques have been successful to give many good microscopic Information for understanding the physical phenomenon

Progress is continuing to obtain better resolution and experimental data and for unconventional new materials